



# 74AHCT595

## 8-Bit Serial-In/Serial-Out or Parallel-Out Shift Register with Output Latches

### GENERAL DESCRIPTION

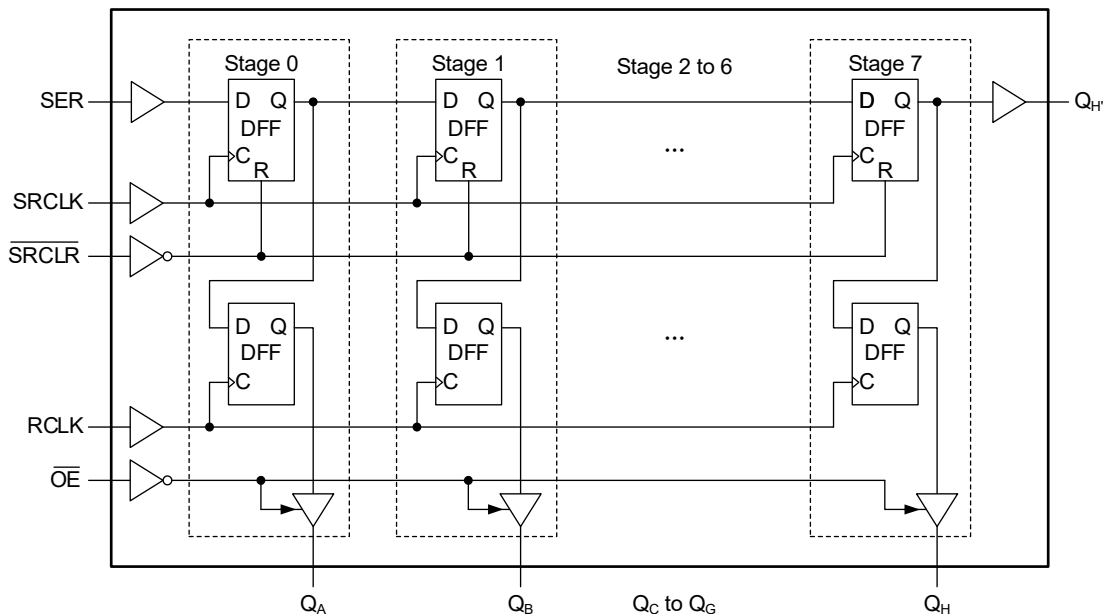
The 74AHCT595 is an 8-bit serial-in/serial-out or parallel-out shift register with output latches designed for 4.5V to 5.5V  $V_{CC}$  operation.

The device integrates an 8-bit shift register and an 8-bit D-type storage register. The storage register features parallel 3-state outputs. The shift register provides a clear input ( $\overline{SRCLR}$ ) with direct overriding function, a serial input (SER) and a serial output ( $Q_H$ ) to implement cascading. When output enable input ( $\overline{OE}$ ) is held low, the data in storage register will appear at the outputs. When  $\overline{OE}$  is held high, all parallel outputs are in high-impedance state.

Both the shift register and storage register have separate clocks. The shift register clock (SRCLK) and storage register clock (RCLK) are positive-edge triggered.

The 74AHCT595 is available in Green TSSOP-16 and SOIC-16 packages. It operates over a temperature range of -40°C to +125°C.

### LOGIC DIAGRAM



### FEATURES

- **Supply Voltage Range: 4.5V to 5.5V**
- **Direct Clear Input of Shift Register**
- **Inputs are Compatible with TTL-Voltage**
- **Latch-Up Performance (> 100mA) Meets JESD 78, Class II Standard**
- **-40°C to +125°C Operating Temperature Range**
- **Available in Green TSSOP-16 and SOIC-16 Packages**

### APPLICATIONS

- Computing: Server, PC, Notebook, Network Switch
- Telecom Equipment
- Medical Equipment
- Industrial Equipment

# 8-Bit Serial-In/Serial-Out or Parallel-Out Shift Register with Output Latches

## 74AHCT595

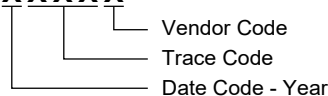
### PACKAGE/ORDERING INFORMATION

MODEL	PACKAGE DESCRIPTION	SPECIFIED TEMPERATURE RANGE	ORDERING NUMBER	PACKAGE MARKING	PACKING OPTION
74AHCT595	TSSOP-16	-40°C to +125°C	74AHCT595XTS16G/TR	0LA XTS16 XXXXX	Tape and Reel, 4000
	SOIC-16	-40°C to +125°C	74AHCT595XS16G/TR	74AHCT595XS16 XXXXX	Tape and Reel, 2500

### MARKING INFORMATION

NOTE: XXXXX = Date Code, Trace Code and Vendor Code.

**XXXXX**



Green (RoHS & HSF): SG Micro Corp defines "Green" to mean Pb-Free (RoHS compatible) and free of halogen substances. If you have additional comments or questions, please contact your SGMICRO representative directly.

### ABSOLUTE MAXIMUM RATINGS <sup>(1)</sup>

Supply Voltage Range, $V_{CC}$ .....	-0.5V to 7.0V
Input Voltage Range, $V_I$ <sup>(2)</sup> .....	-0.5V to 7.0V
Output Voltage Range, $V_O$ <sup>(2)</sup> .....	-0.5V to MIN(7.0V, $V_{CC} + 0.5V$ )
Input Clamp Current, $I_{IK}$ ( $V_I < 0V$ ) .....	-20mA
Output Clamp Current, $I_{OK}$ ( $V_O < 0V$ or $V_O > V_{CC}$ ) .....	$\pm 20mA$
Continuous Output Current, $I_O$ ( $V_O = 0V$ to $V_{CC}$ ) .....	$\pm 25mA$
Continuous Current through $V_{CC}$ or GND .....	$\pm 50mA$
Junction Temperature <sup>(3)</sup> .....	+150°C
Storage Temperature Range .....	-65°C to +150°C
Lead Temperature (Soldering, 10s) .....	+260°C
ESD Susceptibility	
HBM .....	2000V
CDM .....	1000V

### RECOMMENDED OPERATING CONDITIONS

Supply Voltage Range, $V_{CC}$ .....	4.5V to 5.5V
Input Voltage Range, $V_I$ <sup>(4)</sup> .....	0V to 5.5V
Output Voltage Range, $V_O$ .....	0V to $V_{CC}$
Input Transition Rise or Fall Rate, $\Delta t/\Delta V$	
$V_{CC} = 4.5V$ to 5.5V .....	20ns/V (MAX)
Operating Temperature Range .....	-40°C to +125°C

### OVERSTRESS CAUTION

1. Stresses beyond those listed in Absolute Maximum Ratings may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect reliability. Functional operation of the device at any conditions beyond those indicated in the Recommended Operating Conditions section is not implied.
2. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.
3. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability.
4. Unused input pins must be held at  $V_{CC}$  or GND to guarantee the device in normal operation.

### ESD SENSITIVITY CAUTION

This integrated circuit can be damaged if ESD protections are not considered carefully. SGMICRO recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because even small parametric changes could cause the device not to meet the published specifications.

### DISCLAIMER

SG Micro Corp reserves the right to make any change in circuit design, or specifications without prior notice.

FUNCTION TABLE

INPUTS					FUNCTION
SER	SRCLK	SRCLR	RCLK	OE	
X	X	X	X	H	Outputs (Q <sub>A</sub> ~ Q <sub>H</sub> ) are disabled.
X	X	X	X	L	Outputs (Q <sub>A</sub> ~ Q <sub>H</sub> ) are enabled.
X	X	L	X	X	Data of the shift register is cleared.
L	↑	H	X	X	Logic low-level shifted into shift register stage 0. Other stages can transfer data from the previous stage respectively.
H	↑	H	X	X	Logic high-level shifted into shift register stage 0. Other stages can transfer data from the previous stage respectively.
X	X	X	↑	X	Data of the shift register is transferred to the storage register.

H = High Voltage Level

L = Low Voltage Level

↑ = Low-to-High Clock Transition

X = Don't Care

TIMING DIAGRAM

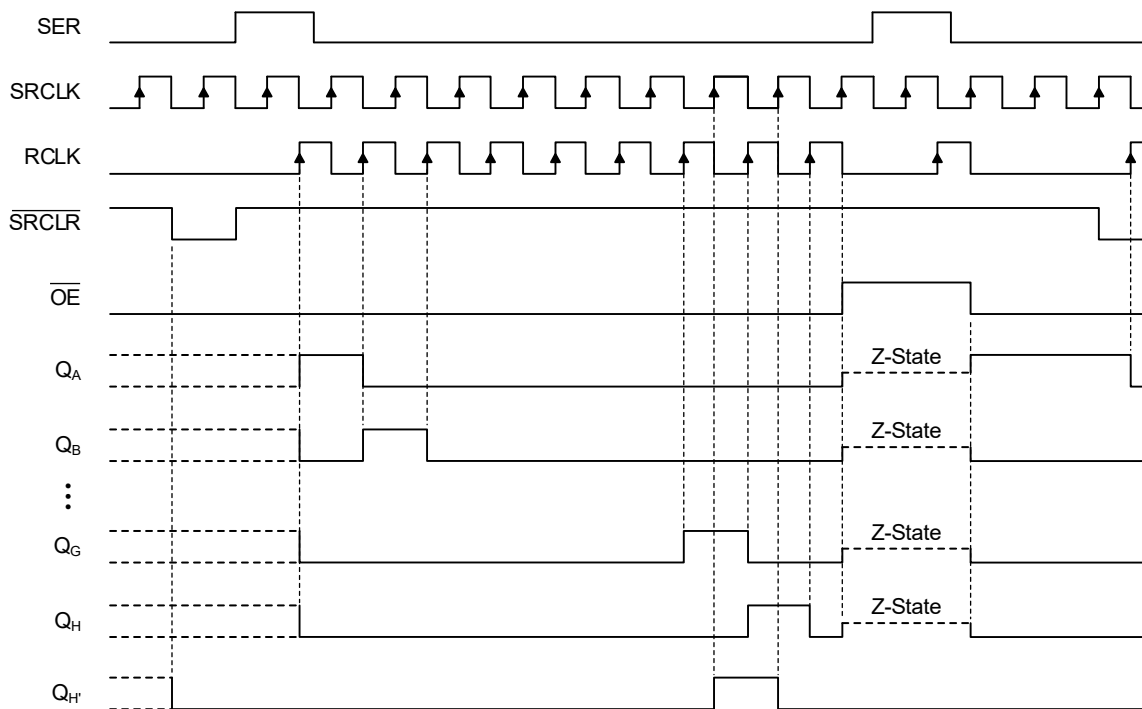
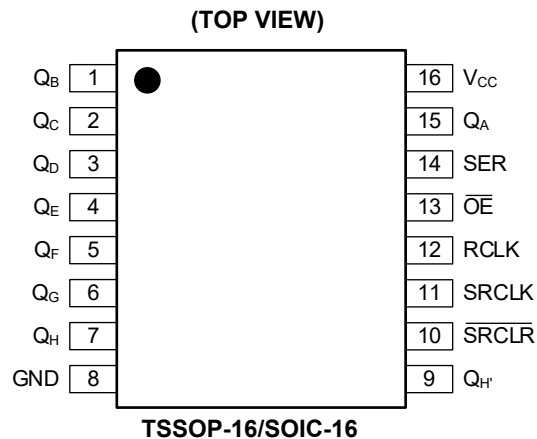


Figure 1. Timing Diagram

## PIN CONFIGURATIONS



## PIN DESCRIPTION

PIN	NAME	FUNCTION
15, 1, 2, 3, 4, 5, 6, 7	$Q_A, Q_B, Q_C, Q_D, Q_E, Q_F, Q_G, Q_H$	Parallel Data Outputs.
8	GND	Ground.
9	$Q_{H'}$	Serial Data Output.
10	$\overline{SRCLR}$	Shift Register Clear Input (Active-Low).
11	SRCLK	Shift Register Clock Input (Rising Edge Triggered).
12	RCLK	Storage Register Clock Input (Rising Edge Triggered).
13	$\overline{OE}$	Output Enable Input (Active-Low).
14	SER	Serial Data Input.
16	$V_{CC}$	Power Supply.

**ELECTRICAL CHARACTERISTICS**(Full = -40°C to +125°C, all typical values are measured at  $T_A = +25^\circ\text{C}$ , unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS	TEMP	MIN	TYP	MAX	UNITS
High-Level Input Voltage	$V_{IH}$		Full	2			V
Low-Level Input Voltage	$V_{IL}$		Full			0.8	V
High-Level Output Voltage	$V_{OH}$	$V_{CC} = 4.5\text{V}, I_{OH} = -50\mu\text{A}$	Full	4.4	4.495		V
		$V_{CC} = 4.5\text{V}, I_{OH} = -8\text{mA}$	Full	4.0	4.28		
		$V_{CC} = 5.5\text{V}, I_{OH} = -8\text{mA}$	Full	5.08	5.31		
Low-Level Output Voltage	$V_{OL}$	$V_{CC} = 4.5\text{V}, I_{OL} = 50\mu\text{A}$	Full		0.005	0.10	V
		$V_{CC} = 4.5\text{V}, I_{OL} = 8\text{mA}$	Full		0.21	0.44	
		$V_{CC} = 5.5\text{V}, I_{OL} = 8\text{mA}$	Full		0.20	0.42	
Input Leakage Current	$I_I$	$V_{CC} = 0$ to $5.5\text{V}, V_I = V_{CC}$ or GND	Full			$\pm 2$	$\mu\text{A}$
Off-State Output Current	$I_{OZ}$	$Q_A \sim Q_H, V_{CC} = 5.5\text{V}, V_O = V_{CC}$ or GND	Full			$\pm 2$	$\mu\text{A}$
Supply Current	$I_{CC}$	$V_{CC} = 5.5\text{V}, V_I = V_{CC}$ or GND, $I_O = 0\text{A}$	Full			20	$\mu\text{A}$
Additional Supply Current <sup>(1)</sup>	$\Delta I_{CC}$	$V_{CC} = 5.5\text{V}$ , one input at $3.4\text{V}$ , other inputs at $V_{CC}$ or GND	Full			1	mA
Input Capacitance	$C_I$	$V_{CC} = 5.0\text{V}, V_I = V_{CC}$ or GND	+25°C		4.5		pF
Output Capacitance	$C_O$	$V_{CC} = 5.0\text{V}, V_O = V_{CC}$ or GND	+25°C		6		pF

NOTE:

1. It is the increase in supply current for per input at the specified TTL voltage levels except  $V_{CC}$  or GND.**NOISE CHARACTERISTICS**(Full = -40°C to +125°C, all typical values are measured at  $V_{CC} = 5.0\text{V}$ ,  $C_L = 50\text{pF}$  and  $T_A = +25^\circ\text{C}$ , unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS	TEMP	MIN	TYP	MAX	UNITS
Maximum Dynamic Low-Level Output Voltage	$V_{OLDMAX}$	Quiet output	+25°C		1		V
Minimum Dynamic Low-Level Output Voltage	$V_{OLDMIN}$	Quiet output	+25°C		-0.6		V
Minimum Dynamic High-Level Output Voltage	$V_{OHDMIN}$	Quiet output	+25°C		3.2		V
Dynamic High-Level Input Voltage	$V_{IHD}$		Full	2			V
Dynamic Low-Level Input Voltage	$V_{ILD}$		Full			0.8	V

## DYNAMIC CHARACTERISTICS

(See Figure 2 for test circuit. Full = -40°C to +125°C, all typical values are measured at  $V_{CC} = 5.0V \pm 0.5V$  and  $T_A = +25^\circ C$ , unless otherwise noted.)

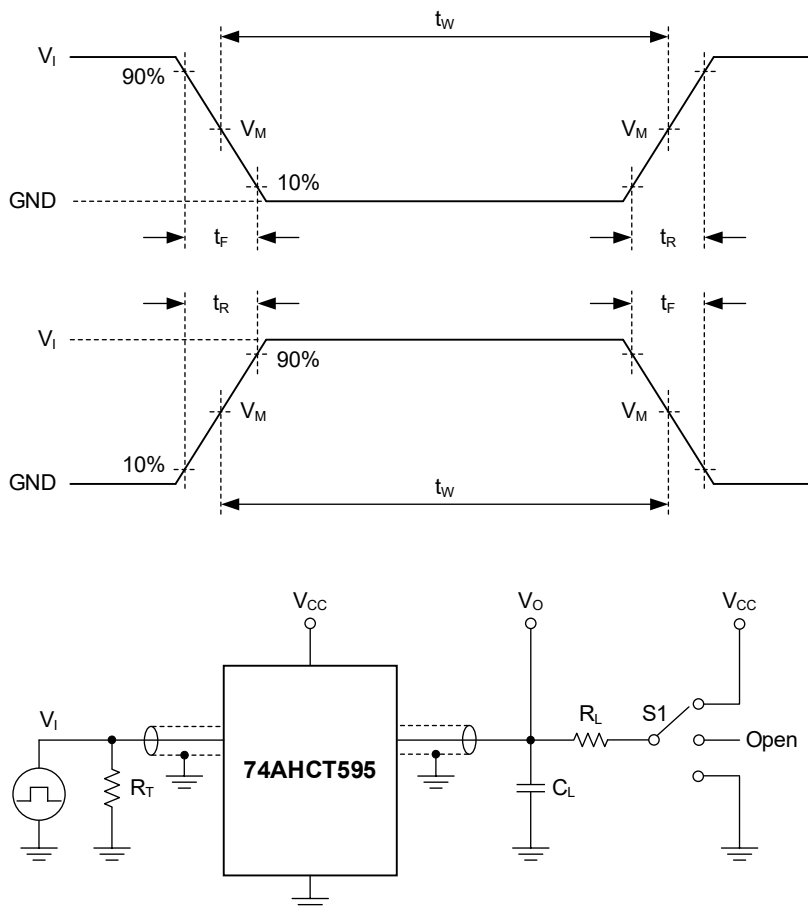
PARAMETER	SYMBOL	CONDITIONS	TEMP	MIN <sup>(1)</sup>	TYP	MAX <sup>(1)</sup>	UNITS	
Low-to-High Propagation Delay	$t_{PLH}$	RCLK to $Q_A \sim Q_H$	$C_L = 15pF$	Full	1	4	8.5	ns
			$C_L = 50pF$	Full	1	5.5	11.5	
High-to-Low Propagation Delay	$t_{PHL}$	RCLK to $Q_A \sim Q_H$	$C_L = 15pF$	Full	1	4	8.5	ns
			$C_L = 50pF$	Full	1	5.5	11.5	
Low-to-High Propagation Delay	$t_{PLH}$	SRCLK to $Q_H$	$C_L = 15pF$	Full	1	4	8.5	ns
			$C_L = 50pF$	Full	1	5.5	11.4	
High-to-Low Propagation Delay	$t_{PHL}$	SRCLK to $Q_H$	$C_L = 15pF$	Full	1	4	8.5	ns
			$C_L = 50pF$	Full	1	5.5	11.4	
High-to-Low Propagation Delay	$t_{PHL}$	$\overline{SRCLR}$ to $Q_H$	$C_L = 15pF$	Full	1	8	13.5	ns
			$C_L = 50pF$	Full	1	10	16	
Off-to-High Propagation Delay	$t_{PZH}$	$\overline{OE}$ to $Q_A \sim Q_H$	$C_L = 15pF$	Full	1	6.5	10.5	ns
			$C_L = 50pF$	Full	1	8	13.5	
Off-to-Low Propagation Delay	$t_{PZL}$	$\overline{OE}$ to $Q_A \sim Q_H$	$C_L = 15pF$	Full	1	6	10.5	ns
			$C_L = 50pF$	Full	1	8	13.5	
High-to-Off Propagation Delay	$t_{PHZ}$	$\overline{OE}$ to $Q_A \sim Q_H$	$C_L = 15pF$	Full	1	3	6.5	ns
			$C_L = 50pF$	Full	1	4	8.5	
Low-to-Off Propagation Delay	$t_{PLZ}$	$\overline{OE}$ to $Q_A \sim Q_H$	$C_L = 15pF$	Full	1	3	6.5	ns
			$C_L = 50pF$	Full	1	4	8.5	
Maximum Frequency	$f_{MAX}$	$C_L = 15pF$	Full	115	165		MHz	
		$C_L = 50pF$	Full	85	160			
Pulse Width	$t_W$	SRCLK high or low	Full	5.5			ns	
		RCLK high or low	Full	5.5				
		$\overline{SRCLR}$ low	Full	8				
Setup Time <sup>(2)</sup>	$t_{SU}$	SER before SRCLK $\uparrow$	Full	9			ns	
		SRCLK $\uparrow$ before RCLK $\uparrow$	Full	5				
		$\overline{SRCLR}$ low before RCLK $\uparrow$	Full	10				
		$\overline{SRCLR}$ high (inactive) before SRCLK $\uparrow$ <sup>(3)</sup>	Full	5				
Hold Time	$t_H$	SER after SRCLK $\uparrow$	Full	5			ns	
Power Dissipation Capacitance <sup>(4) (5)</sup>	$C_{PD}$	No load, $V_{CC} = 5.0V$ , $f = 10MHz$	+25°C		30		pF	

## NOTES:

- Specified by design and characterization, not production tested.
- The setup time enables the storage register to get stable data from the shift register. In this case where clocks can be tied together, the shift register is a clock pulse in front of the storage register.
- $t_{REC}$  is the same as  $\overline{SRCLR}$  high (inactive) before SRCLK  $\uparrow$ .
- $C_{PD}$  is used to determine the dynamic power dissipation ( $P_D$  in  $\mu W$ ).  

$$P_D = C_{PD} \times V_{CC}^2 \times f_i + \Sigma(C_L \times V_{CC}^2 \times f_o)$$
 where:  
 $f_i$  = Input frequency in MHz.  
 $f_o$  = Output frequency in MHz.  
 $C_L$  = Output load capacitance in pF.  
 $V_{CC}$  = Supply voltage in Volts.  
 $\Sigma(C_L \times V_{CC}^2 \times f_o)$  = Sum of outputs.
- All 9 outputs switching.

TEST CIRCUIT



Test conditions are given in Table 1.

Definitions test circuit:

$R_L$ : Load resistance.

$C_L$ : Load capacitance (includes jig and probe).

$R_T$ : Termination resistance (equals to output impedance  $Z_O$  of the pulse generator).

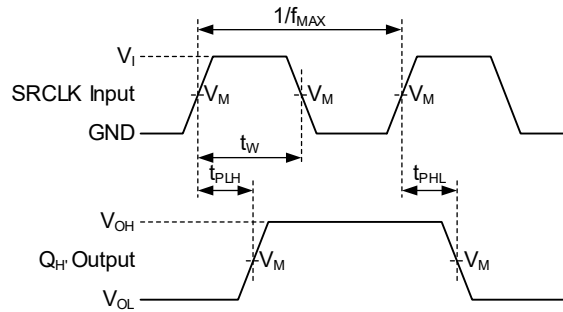
S1: Test selection switch.

Figure 2. Test Circuit for Measuring Switching Times

Table 1. Test Conditions

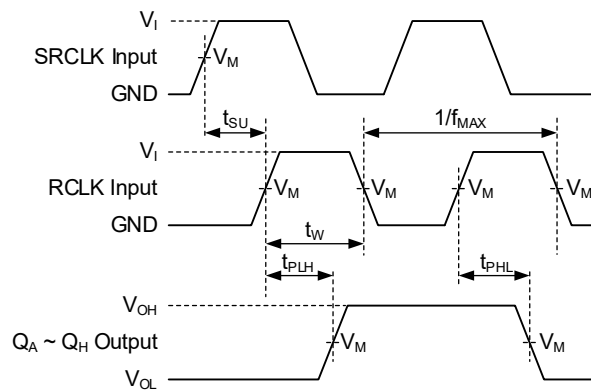
SUPPLY VOLTAGE	INPUT		LOAD		S1 POSITION		
$V_{CC}$	$V_I$	$t_R, t_F$	$C_L$	$R_L$	$t_{PHL}, t_{PLH}$	$t_{PZH}, t_{PHZ}$	$t_{PZL}, t_{PLZ}$
4.5V to 5.5V	$V_{CC}$	$\leq 3.0ns$	15pF, 50pF	1k $\Omega$	Open	GND	$V_{CC}$

WAVEFORMS



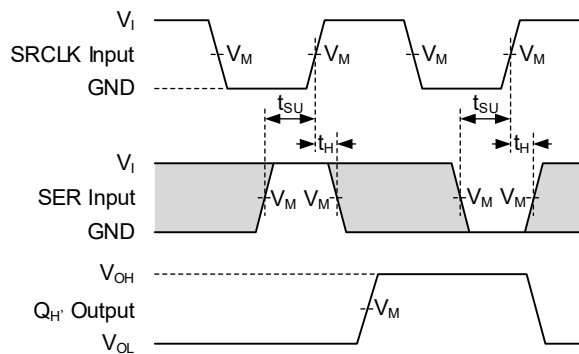
Test conditions are given in Table 1.  
 Measurement points are given in Table 2.  
 Logic levels:  $V_{OL}$  and  $V_{OH}$  are typical output voltage levels that occur with the output load.

Figure 3. Shift Register Clock Input to Output Propagation Delay Times, Pulse Width and Maximum Frequency



Test conditions are given in Table 1.  
 Measurement points are given in Table 2.  
 Logic levels:  $V_{OL}$  and  $V_{OH}$  are typical output voltage levels that occur with the output load.

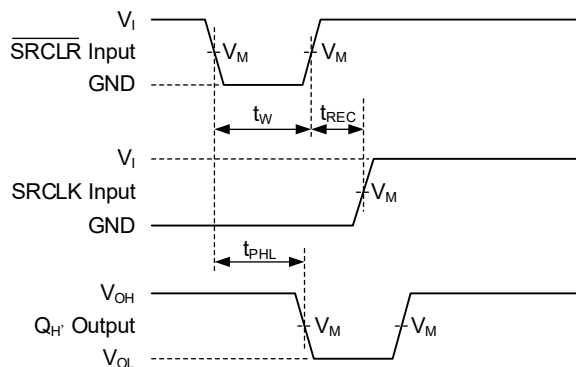
Figure 4. Storage Register Clock Input to Output Propagation Delay Times, Shift Register Clock to Storage Register Clock Setup Time, Pulse Width and Maximum Frequency



Test conditions are given in Table 1.  
 Measurement points are given in Table 2.  
 Logic levels:  $V_{OL}$  and  $V_{OH}$  are typical output voltage levels that occur with the output load.  
 The shaded areas refer to when the input is allowed to change for predictable output performance.

Figure 5. Data Setup and Hold Times

WAVEFORMS (continued)

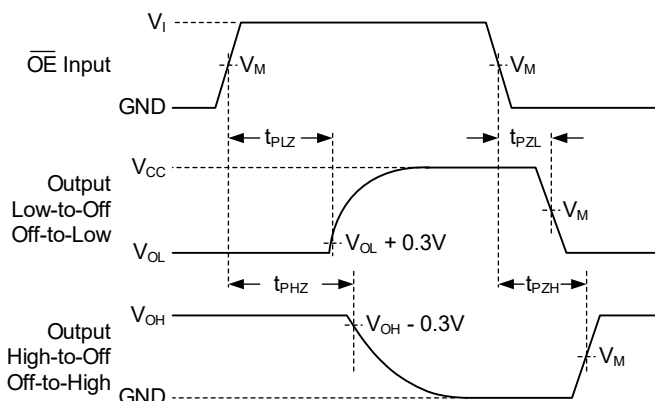


Test conditions are given in Table 1.

Measurement points are given in Table 2.

Logic levels:  $V_{OL}$  and  $V_{OH}$  are typical output voltage levels that occur with the output load.

Figure 6. Clear Input to Output Propagation Delay Times, Pulse Width and Recovery Time



Test conditions are given in Table 1.

Measurement points are given in Table 2.

Logic levels:  $V_{OL}$  and  $V_{OH}$  are typical output voltage levels that occur with the output load.

Figure 7. Enable and Disable Times

Table 2. Measurement Points

SUPPLY VOLTAGE	INPUT		OUTPUT
$V_{CC}$	$V_I$	$V_M^{(1)}$	$V_M$
4.5V to 5.5V	$V_{CC}$	$0.5 \times V_{CC}$	$0.5 \times V_{CC}$

NOTE:

1. The measurement points should be  $V_{IH}$  or  $V_{IL}$  when the input rising or falling time exceeds 3.0ns.

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## REVISION HISTORY

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

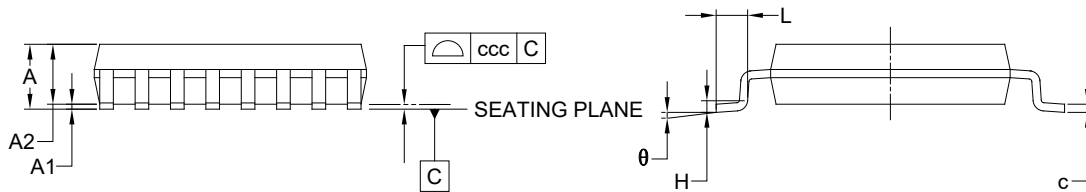
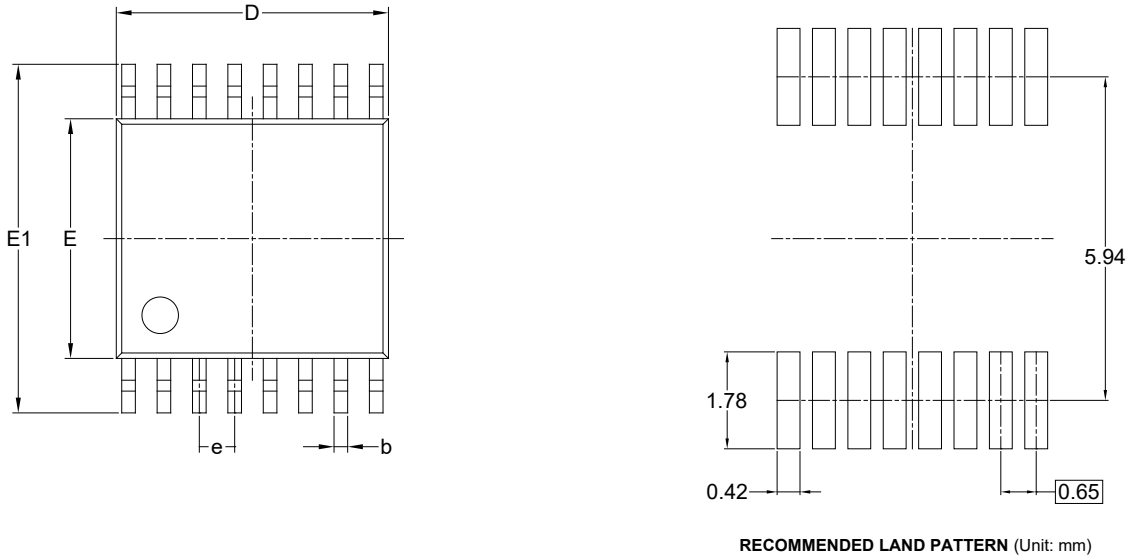
<b>MAY 2026 – REV.A to REV.A.1</b>	<b>Page</b>
Updated General Description section.....	1
Updated Features section.....	1
Updated Recommended Operating Conditions section.....	2
Updated Package Outline Dimensions section .....	12

<b>Changes from Original (OCTOBER 2023) to REV.A</b>	<b>Page</b>
Changed from product preview to production data.....	All

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PACKAGE OUTLINE DIMENSIONS

TSSOP-16



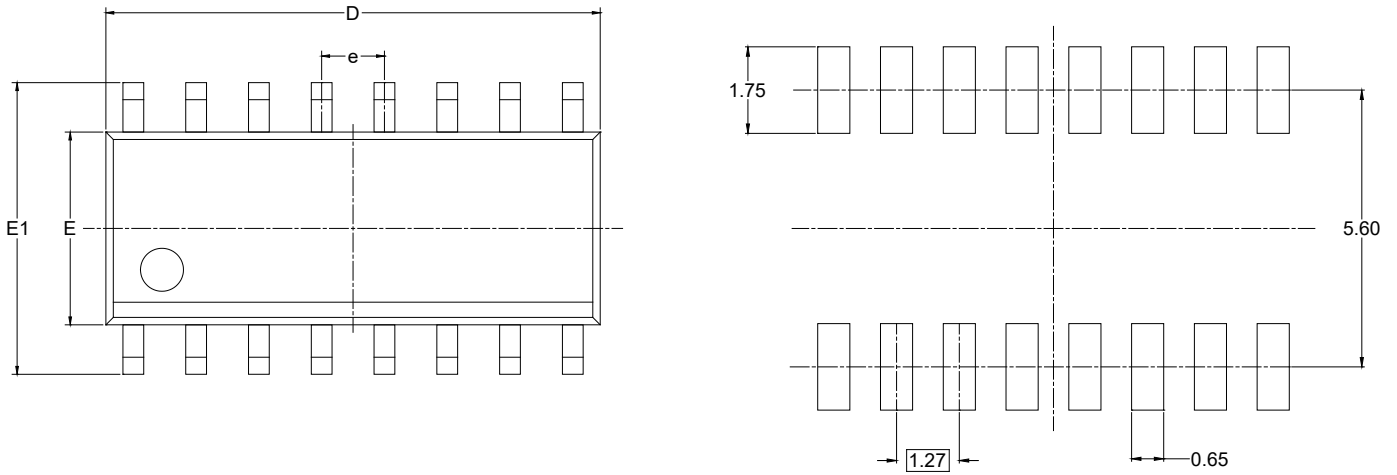
Symbol	Dimensions In Millimeters		
	MIN	NOM	MAX
A	-	-	1.200
A1	0.050	-	0.150
A2	0.800	-	1.050
b	0.190	-	0.300
c	0.090	-	0.200
D	4.860	-	5.100
E	4.300	-	4.500
E1	6.200	-	6.600
e	0.650 BSC		
L	0.450	-	0.750
H	0.250 TYP		
$\theta$	0°	-	8°
ccc	0.100		

- NOTES:
1. This drawing is subject to change without notice.
  2. The dimensions do not include mold flashes, protrusions or gate burrs.
  3. Reference JEDEC MO-153.

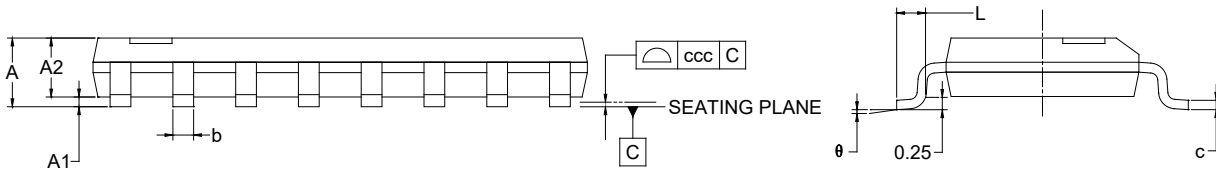
# PACKAGE INFORMATION

## PACKAGE OUTLINE DIMENSIONS

### SOIC-16



RECOMMENDED LAND PATTERN (Unit: mm)



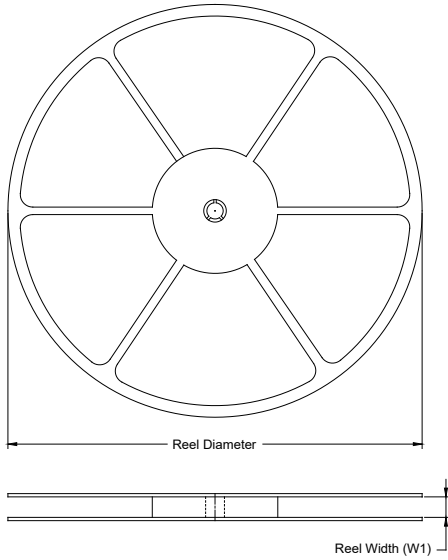
Symbol	Dimensions In Millimeters		
	MIN	NOM	MAX
A	-	-	1.750
A1	0.100	-	0.250
A2	1.250	-	1.550
b	0.310	-	0.510
c	0.100	-	0.250
D	9.800	-	10.200
E	3.800	-	4.000
E1	5.800	-	6.200
e	1.270 BSC		
L	0.400	-	1.270
$\theta$	0°	-	8°
ccc	0.100		

NOTES:

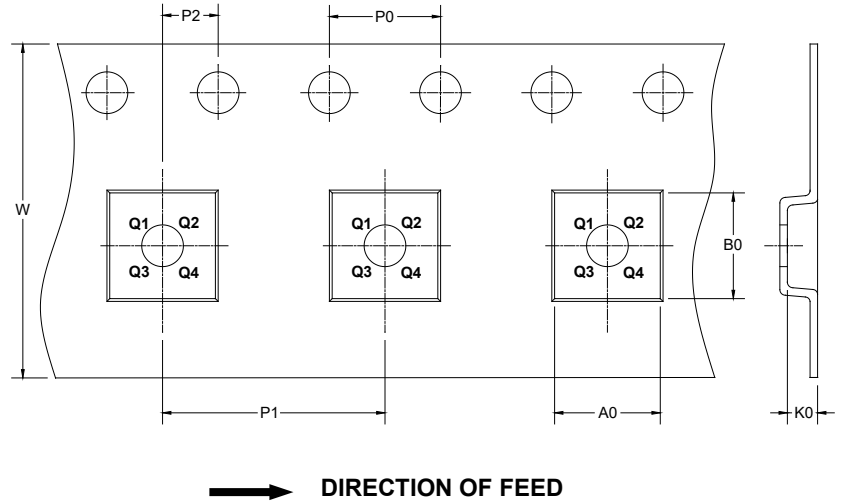
1. This drawing is subject to change without notice.
2. The dimensions do not include mold flashes, protrusions or gate burrs.
3. Reference JEDEC MS-012.

TAPE AND REEL INFORMATION

REEL DIMENSIONS



TAPE DIMENSIONS



NOTE: The picture is only for reference. Please make the object as the standard.

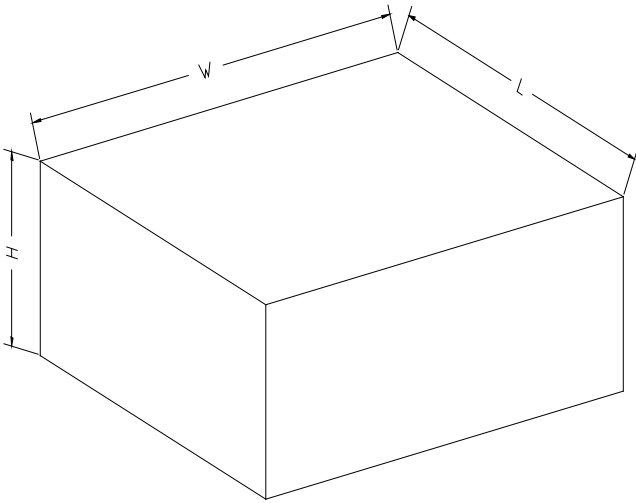
KEY PARAMETER LIST OF TAPE AND REEL

Package Type	Reel Diameter	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P0 (mm)	P1 (mm)	P2 (mm)	W (mm)	Pin1 Quadrant
TSSOP-16	13"	12.4	6.80	5.40	1.50	4.0	8.0	2.0	12.0	Q1
SOIC-16	13"	16.4	6.50	10.30	2.10	4.0	8.0	2.0	16.0	Q1

DD0001

# PACKAGE INFORMATION

## CARTON BOX DIMENSIONS



NOTE: The picture is only for reference. Please make the object as the standard.

## KEY PARAMETER LIST OF CARTON BOX

Reel Type	Length (mm)	Width (mm)	Height (mm)	Pizza/Carton
13"	386	280	370	5

DD0002